



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Datacolor Technology (Suzhou) Co., Ltd

**288 Shengpu Road
Suzhou Jiangsu, China 215021**

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 20 February 2027

Certificate Number: AC-1759



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

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CALIBRATION

Valid to: **February 20, 2027**

Certificate Number: **AC-1759**

Photometry and Radiometry

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
8°:t Geometry – Spectral Reflectance Factor	(1 to 100) %R (360 to 370) nm (380 to 390) nm (400 to 750) nm	0.54 %R 0.44 %R 0.38 %R	Comparison to CERAM Ceramic White Tile, M2009 Spectrometer, JYG 453-2002
8°:d Geometry - Spectral Reflectance Factor	(1 to 100) %R (360 to 370) nm (380 to 390) nm (400 to 750) nm	0.51 %R 0.43 %R 0.37 %R	Comparison to CERAM Ceramic White Tile, M2009 Spectrometer, JYG 453-2002
d:0° Geometry - Spectral Reflectance Factor	(1 to 100) %R (360 to 370) nm (380 to 700) nm	0.67 %R	Comparison to CERAM Ceramic White Tile, Elrepho Spectrometer, JYG 453-2002
Absolute 0°:45°- Bidirectional Spectral Reflectance Factor	(1 to 100) %R (400 to 410) nm (420 to 700) nm	0.87 %R 0.79 %R	Comparison to CERAM Ceramic White Tile, DC245 Spectrometer, JYG 453-2002

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. The uncertainty term R represents Spectral Reflectance.
2. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1759.



Jason Stine, Vice President